

IN THE SPECIFICATION

Please amend the specification as follows:

Replace the paragraph on page 4, on line 8 of the specification with the following:

$$\lambda/8n_{L0} \leq d_{L0} \leq 3\lambda/8n_{L0} - \lambda/8n_{L0} \leq d_{L0} \leq 3\lambda/8n_{L0}$$

Replace the paragraph on page 5, between lines 19-24 of the specification with the following:

As shown in ~~Fig 10~~ Figs. 10a-10b, the first auxiliary layer I1 below the first metal reflective layer indeed increases the stack's transmission and decreases its reflectivity, while the position of the R- and T-extrema stays (nearly) the same. The optimum recording layer thickness is determined by the first maximum in reflection, which is given by $\text{Max}(R) \rightarrow \lambda/2n_{L0}(1-\Delta)$, where $\Delta \sim 1/8$ to $1/4$ is a phase shift introduced by the metal. The preferred recording layer thickness for this stack becomes: